

Message Text

CONFIDENTIAL

PAGE 01 OECD P 05838 071015Z

10

ACTION EB-07

INFO OCT-01 CIAE-00 COME-00 DODE-00 NSAE-00 TRSE-00 EUR-12

ERDA-05 ISO-00 /025 W

----- 065154

R 071009Z MAR 75

FM USMISSION OECD PARIS

TO SECSTATE WASH DC 5790

C O N F I D E N T I A L OECD PARIS 05838

EXCON

E.O. 11652 XGDS1

TAGS: ESTC, COCOM

SUBJECT: COCOM LIST REVIEW: IML 20 - SUPERCONDUCTORS

REFS: A. COCOM DOC DEF (74) ML 20.1

B. STATE 45749

1. ON 4 MARCH THE GERMAN PROPOSAL FOR CHANGING THE CUT-OFF VALUE IN THE EXCLUSION TO SUBITEM (B) (1) WAS DISCUSSED. THE US GAVE A STATEMENT OF THE INTERPRETATION OF "WIRE (FILAMENTS)" AS NOW SHOWN IN THE DEFINITION. IT WAS NOTED THAT INDUSTRY OFTEN REFERS TO THE MATRIX SYSTEM, I.E. FILAMENT CONTAINED IN METAL MATRIX, AS "WIRE". THE INTERPRETATION APPEARS TO BE THE SAME WITH THE GERMANS. THE US POSED TWO QUESTIONS TO THE GERMAN DELEGATION: (1) WHAT ARE USES OF MATRIX SYSTEMS WITH FILAMENTS OF DIAMETERS BETWEEN 30 AND 75 MICRONS? AND (2) WOULD SOME INTERMEDIATE CUT-OFF SERVE THE PURPOSES AS WELL? US FURTHER INDICATED THAT EXAMPLES B AND C, 33 AND 37 MICRONS RESPECTIVELY, ARE BEING USED IN MILITARY RESEARCH AND DEVELOPMENT FOR CERTAIN PIECES OF EQUIPMENT.

2. CANADA, FRANCE, UK, AND ITALY AGREED. JAPAN AND NETHERLANDS WERE OPENMINDED.

CONFIDENTIAL

CONFIDENTIAL

PAGE 02 OECD P 05838 071015Z

ACTION REQUESTED: PLEASE CHECK GERMAN PROPOSAL OUT WITH

NRL (CHECK WITH JIM BAGLEY FOR BEST SOURCE). IN SPITE
OF R AND D, 30 MICRONS MAY BE REASONABLE. IF NOT, PRO-
VIDE INTERMEDIATE VALUE, E.G. 40 MICRONS, WITH EVALUA-
TION AND JUSTIFICATION. AUTHORIZATION ALSO NEEDED TO
NEGOTIATE CLEAR WORDING FOR PROPOSED GERMAN EXCLUSION
NOTE, INCLUDING MOU OR SOU FOR DEFINING WIRE AND FILA-
MENT, IF NEEDED. INITIAL THOUGHT IS AS FOLLOWS: ".....
EXCEPT SUPERCONDUCTIVE WIRE CONTAINING FILAMENTS WITH AN
INDIVIDUAL FILAMENT CROSS-SECTIONAL AREA OF "X" SQ. MM
("Y" MICRONS DIAMETER) OR GREATER." IMPERATIVE THAT
INSTRUCTIONS BE RECEIVED PRIOR TO 14 MARCH, BECAUSE
BILATERAL DISCUSSIONS HAVE BEEN SCHEDULED WITH GERMAN
EXPERT WHO ARRIVES 17 MARCH.
TURNER

CONFIDENTIAL

NNN

Message Attributes

Automatic Decaptioning: X
Capture Date: 01 JAN 1994
Channel Indicators: n/a
Current Classification: UNCLASSIFIED
Concepts: STRATEGIC TRADE CONTROLS, SEMICONDUCTOR DEVICES, EXCEPTIONS LIST, MEETINGS
Control Number: n/a
Copy: SINGLE
Draft Date: 07 MAR 1975
Decaption Date: 01 JAN 1960
Decaption Note:
Disposition Action: RELEASED
Disposition Approved on Date:
Disposition Authority: GarlanWA
Disposition Case Number: n/a
Disposition Comment: 25 YEAR REVIEW
Disposition Date: 28 MAY 2004
Disposition Event:
Disposition History: n/a
Disposition Reason:
Disposition Remarks:
Document Number: 1975OECDP05838
Document Source: CORE
Document Unique ID: 00
Drafter: n/a
Enclosure: n/a
Executive Order: X1
Errors: N/A
Film Number: D750080-0349
From: OECD PARIS
Handling Restrictions: n/a
Image Path:
ISecure: 1
Legacy Key: link1975/newtext/t19750372/aaaacmua.tel
Line Count: 75
Locator: TEXT ON-LINE, ON MICROFILM
Office: ACTION EB
Original Classification: CONFIDENTIAL
Original Handling Restrictions: n/a
Original Previous Classification: n/a
Original Previous Handling Restrictions: n/a
Page Count: 2
Previous Channel Indicators: n/a
Previous Classification: CONFIDENTIAL
Previous Handling Restrictions: n/a
Reference: 75 COCOM DOC DEF (7ML, 75 20
Review Action: RELEASED, APPROVED
Review Authority: GarlanWA
Review Comment: n/a
Review Content Flags:
Review Date: 13 MAY 2003
Review Event:
Review Exemptions: n/a
Review History: RELEASED <13 MAY 2003 by ElyME>; APPROVED <19 JUN 2003 by GarlanWA>
Review Markings:

Margaret P. Grafeld
Declassified/Released
US Department of State
EO Systematic Review
05 JUL 2006

Review Media Identifier:
Review Referrals: n/a
Review Release Date: n/a
Review Release Event: n/a
Review Transfer Date:
Review Withdrawn Fields: n/a
Secure: OPEN
Status: NATIVE
Subject: COCOM LIST REVIEW: IML 20 - SUPERCONDUCTORS
TAGS: ESTC, GE, US, COCOM
To: STATE
Type: TE
Markings: Margaret P. Grafeld Declassified/Released US Department of State EO Systematic Review 05 JUL 2006